

APQ03SN80AB

800V/3A N-Channel MOSFET

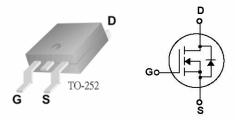
1 Description

These N-Channel enhancement mode power field effect transistors are produced using planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction based on half bridge topology.

2 Features

- 800V / 3A
- $R_{DS(on)} = 3.6\Omega(typ)$, $V_{GS} = 10V$, $I_{D} = 1.5A$
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability..



3 Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol		APQ03SN80AB-XXM0		
	Parameter	APQ03SN80AB-XXM1	Units	
		APQ03SN80AB-XXJ1		
		TO-252		
V_{DSS}	Drain-Source Voltage	800	V	
l _D	Drain Current - Continuous (T _C = 25°C)	3	Α	
	- Continuous (T _C = 100°C)	1.9	Α	
l _{DM}	Drain Current – Pulsed ①	12	Α	
V_{GS}	Gate-Source Voltage	± 30	V	
E _{AS}	Single Pulsed Avalanche Energy ②	320	mJ	
AR	Avalanche Current	3	Α	
E _{AR}	Repetitive Avalanche Energy	10.7	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	4.5	V/ns	
D _D	Power Dissipation (T _C = 25°C)	107	W	
	- De-rate above 25°C	0.85	W/°C	
T_J,T_STG	Operating and Storage Temperature Range	-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8"from case for 5 seconds	300	°C	

^{*} note :

- ① Repetitive Rating: Pulse width limited by maximum junction temperature.
- ② V_{DD} =50V, starting T_J =25°C, L=TBD, R_G =25 Ω , I_{AS} =3A
- ③ ISD ≤ 3A, di/dt ≤ 200A/ μ s, VDD ≤ V_{(BR)DSS}, T_J ≤ 150°C.

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4 Thermal Characteristics

		APQ03SN80AB-XXM0		
Symbol	Parameter	APQ03SN80AB-XXM1	Units	
Symbol	raidiletei	APQ03SN80AB-XXJ1		
		TO-252		
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	1.17	°C/W	
R _{θCS}	Thermal Resistance, Case-to-Sink Typ.	0.5	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W	

5 Electrical Characteristics T_C = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	800			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		1		V/°C
I _{DSS}	Gate to Source leakage current	V _{DS} = 800 V, V _{GS} = 0 V			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Chara	ncteristics					
$V_{GS(th)}$	Gate Threshold Voltage	V _{DS} = VGS, I _D = 250 μA	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On- Resistance	V _{GS} = 10 V, I _D = 1.5 A ④		3.6	5	Ω
Dynamic	Characteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		550		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		55		pF
C _{rss}	Reverse Transfer Capacitance			6		pF
Switchin	g Characteristics					
t _{d(on)}	Turn-On Delay Time	V_{DD} = 400 V, I_{D} = 3A, R_{G} = 25 Ω ④		20		ns
t _r	Turn-On Rise Time			50		ns
•						
$t_{d(off)}$	Turn-Off Delay Time			20		ns
$\frac{t_{d(off)}}{t_{f}}$	Turn-Off Delay Time Turn-Off Fall Time			30		ns ns
	<u> </u>	V _{DS} = 640 V, I _D = 3A,				_
t_f	Turn-Off Fall Time	V _{DS} = 640 V, I _D = 3A, V _{GS} = 10 V ④		30		ns
$\frac{t_{\text{f}}}{Q_{\text{g}}}$	Turn-Off Fall Time Total Gate Charge	, , ,		30 14		ns nC
$\begin{array}{c} t_f \\ Q_g \\ Q_{gs} \\ \end{array}$	Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{GS} = 10 V 4		30 14 3.5	 	ns nC nC
$\begin{array}{c} t_f \\ Q_g \\ Q_{gs} \\ \end{array}$	Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge urce Diode Characteristics a	V _{GS} = 10 V 4		30 14 3.5	 	ns nC nC

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V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 3 A			1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 3 \text{ A},$		640		ns
Q _{rr}	Reverse Recovery Charge	dI _F / dt = 100 A/μs ④	-	4.0		μC

Notes:

- ① Repetitive Rating: Pulse width limited by maximum junction temperature. ② VDD=50V, starting TJ=25 $^{\circ}$ C, L=TBD, RG=25 Ω , IAS=3A
- ③ ISD ≤ 3A, di/dt ≤ 200A/ μ s, VDD ≤ V(BR)DSS, TJ ≤ 150 $^{\circ}$ C
- ⓐ Pulse Test: Pulse width ≤300 μ s, Duty cycle ≤ 2%. Depend on FT Test.
- ⑤ CP Test

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Note

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